



Seeing beyond

Study Structure-Property Relations in Materials Using Analytical and In-Situ Microscopy Characterization Techniques

Agenda

18th August 2019, Sunday

2:00 PM - 6:00 PM

2:00 PM **Registration**

2:30 PM **Internal Structures Evolvement Revealed by Laboratory X-ray Tomography**

Prof. Zhang Lei

Shenyang National Laboratory of Materials Science, Institute of Metal Research, Chinese Academy of Sciences

3:05 PM **In-Situ X-Ray Microscopy and LabDCT on Material Science Applications**

Dr. Nan Liu

X-ray Microscopy Application Specialist, ZEISS Research Microscopy Solutions

3:40 PM Coffee Break

4:05 PM **FIB-SEM and Laser Ablation Applications in Material Science**

Dr. Qijun Ren

Electron Microscopy Application Engineer, ZEISS Research Microscopy Solutions

4:40 PM **Machine Learning Segmentation of Metal Samples**

Dr. Roger Barnett

Application Development Engineer: Steel & Other Metals, ZEISS Research Microscopy Solutions

5:15 PM **Using Transmission Kikuchi Diffraction in a Scanning Electron Microscope to Quantify Geometrically Necessary Dislocation Density at the Nanoscale**

Prof. Hongbiao Dong

Department of Engineering, University of Leicester

6:00 PM **End of Workshop**

Speakers and Abstracts

Prof. Lei Zhang

Shenyang National Laboratory of Materials Science, Institute of Metal Research, Chinese Academy of Sciences

Title: Internal Structures Evolvement Revealed by Laboratory X-ray Tomography

Abstract: Although X-ray generated from laboratory-based tubes cannot be compared with synchrotron radiation in brilliance and monochromaticity, they are still viable and accessible in-house for ex-situ or interrupted in situ X-ray tomography. This talk mainly demonstrates recent works using laboratory X-ray tomography coupled with the measurements of properties or performance testing under thermal, mechanical, and electrical conditions. Evolvements of correlated internal structures for some typical materials were uncovered. The damage features in a graded metallic 3D mesh and a metallic glass under mechanical loading were revealed and investigated. Micro-voids with thermal treatment and void healing phenomenon with electropulsing were clearly demonstrated and quantitatively analyzed. The substance transfer around an electrode of a Li-S battery and the protective performance of a Fe-based metallic glass coating on stainless steel were monitored through electrochemical processes. It was shown that in situ studies of the laboratory X-ray tomography were suitable for the investigation of structure change under controlled conditions and environments. An extension of the research for in situ laboratory X-ray tomography can be expected with supplementary novel techniques for internal strain, global 3D grain orientation, and a fast tomography strategy.

Mr. Nan Liu

X-ray Microscopy Application Specialist, ZEISS Research Microscopy Solutions

Title: In-Situ X-Ray Microscopy and LabDCT on Material Science Applications

Abstract: The presentation will introduce the advantages of ZEISS X-ray microscopy and its applications in metal research. The first section of the presentation is focused mainly on the working principle and instrumentation in X-ray microscopy. The following sections will list the application cases of XRM on metal research, including alloy, AM, TBC, 4D in-situ experiment etc. The last sections will introduce diffraction contrast tomography technology on ZEISS x-ray microscopy. The application of DCT in metal crystal orientation analysis will also be introduced.



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Dr. Qijun Ren

Electron Microscopy Application Engineer, ZEISS Research Microscopy Solutions

Title: FIB-SEM and Laser Ablation Applications in Material Science

Abstract: FIB-SEM is commonly used in material science for high resolution imaging, TEM sample preparation, and 3D reconstruction of samples, etc. However, the complexity of the workflow and difficulty to access regions of interests (ROI) deeply buried under sample surface hindered more effective applications of FIB-SEM in material characterizations. On the other hand, the analysis of materials such as elemental composition in high resolution is highly demanding, which is also beyond the scope of traditional EDS analysis.

To address the above issues, we introduced the new generation of ZEISS FIB-SEM system. With new designed workflows, it provides much higher efficiencies for traditional time consuming applications, such as TEM sample preparation and 3D tomography. The correlation of a Femto-second laser ablation and Ga FIB fine milling realizes the position and access to the ROIs deeply buried in bulk materials. These techniques pave the way for effective characterization of samples in nanometer scale and in 3D, and will find wide applications in Alloys, Metals, Semiconductors, and Additive manufacturing, etc. Moreover, correlation between FIB-SEM and a nano-SIMS (Secondary Ion Mass Spectroscopy) system allows for high resolution and 3D elemental analysis quantitatively, which helps for deep understanding of samples.

Dr. Roger Barnett

Application Development Engineer: Steel & Other Metals, ZEISS Research Microscopy Solutions

Title: Machine Learning Segmentation of Metal Samples

Abstract: Most routine assessment of steel and other metals requires microscopy to assess various microstructural parameters intrinsic to the metal or the effects of subsequent treatments. These may include grain size, porosity, coating layer thickness or a variety of other factors.

Quantitative assessment of micrographs involves a segmentation step – dividing one region from another. Regions may be individual grains, pores, dendrites, layers or phases. Doing this by assessing colour/greyscale levels may be a challenging and time-consuming task.

We present a new approach for straightforward workflow-based segmentation of metal sample images using guided machine learning in ZEISS ZEN Intellesis. This facilitates faster routine analysis and even allows quantitative automatic assessment of challenging samples that would normally require manual labelling. The technique can be applied to light microscopy, electron microscopy, X-ray microscopy – any microscopic method



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Prof. Hongbiao Dong

Department of Engineering, University of Leicester

Title: Using Transmission Kikuchi Diffraction in a Scanning Electron Microscope to Quantify Geometrically Necessary Dislocation Density at the Nanoscale

Abstract: Quantification of GND density on mesoscale has been achieved with recent advances in automated orientation imaging microscopy by electron backscatter diffraction (EBSD). In EBSD, the Kikuchi diffraction patterns arise as a consequence of diffraction within the subsurface interaction volume, which is fully contained within the bulk material. As a result, the spatial resolution for measuring GND density is restricted to approximately 100 nm. Therefore, it is challenging to quantify the geometrically necessary dislocation (GND) density at the nanoscale using conventional electron backscatter diffraction due to its limited spatial resolution.

To overcome this problem, in this study, the transmission Kikuchi diffraction (TKD) technique is used to measure lattice orientation and to calculate the corresponding nanoscale GND density. Using the TKD method, a variation of GND density from 6.0×10^{14} to $1.0 \times 10^{16} \text{ m}^{-2}$ has been measured in a welded super duplex stainless steel sample. The distribution of dislocation density is shown to be in good agreement with transmission electron microscope (TEM) result. Compared with dislocation measurements obtained by TEM, the TKD-GND method is revealed to be a relatively accurate, fast and accessible method.